

Thin film growth of chiral magnet YbNi_3Al_9

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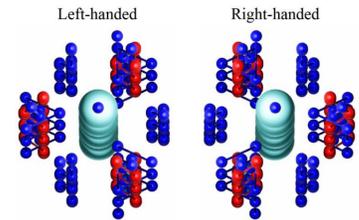
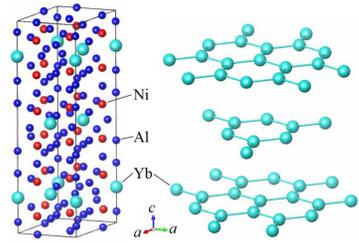
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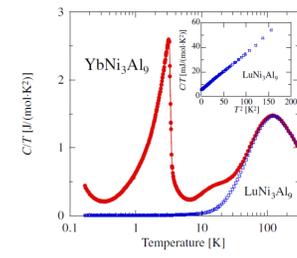
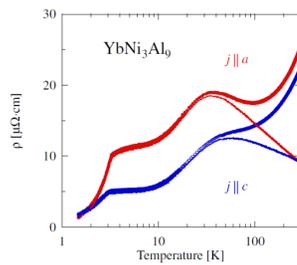
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Heavy fermion chiral magnet YbNi_3Al_9

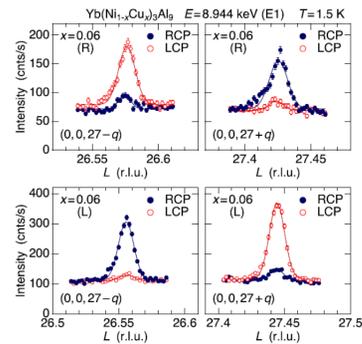


Crystal structure
 ✓ Trigonal
 ✓ $R\bar{3}2$ (Sohncke space group)
 ✓ $a = 7.2731 \text{ \AA}$, $c = 27.582 \text{ \AA}$



T. Yamashita *et al.*, JPSJ **81**, 034705 (2012).

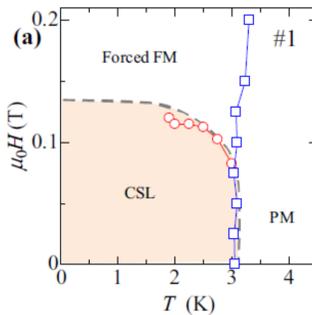
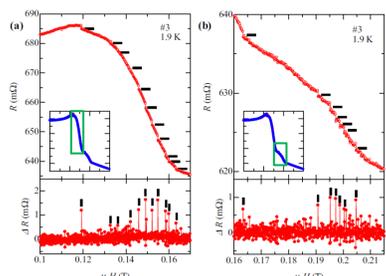
Heavy fermion
 ✓ Dense Kondo effect
 ✓ Large electronic specific heat coefficient
 $\gamma = 100 \text{ mJ/K}^2 \cdot \text{mol}$



T. Matsumura *et al.*, JPSJ **86**, 124702 (2017).

✓ Chiral magnet
 $T_m = 3.4 \text{ K}$
 $q = (0, 0, -0.82)$
 $L_0 \sim 3.4 \text{ nm}$

✓ Formation of the chiral soliton lattice (CSL)



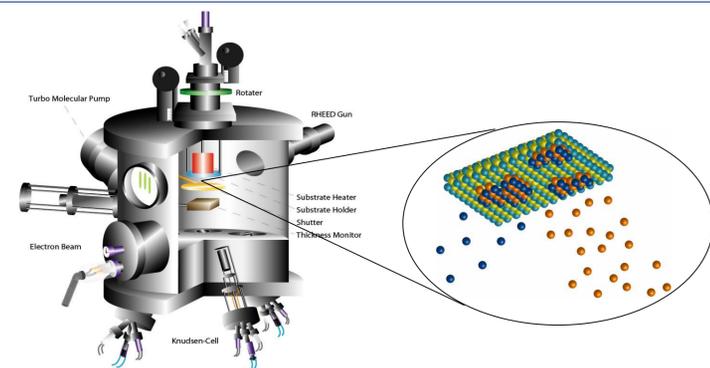
R. Aoki *et al.*, PRB **97**, 214414 (2018).

Motivation

- ✓ Utilizing chiral spin order for device applications
- ✓ Carrier density control by applying a strong electric field
 → Control material parameters (e.g. T_m , H_c)

Establishing a method for thin film growth of chiral magnets

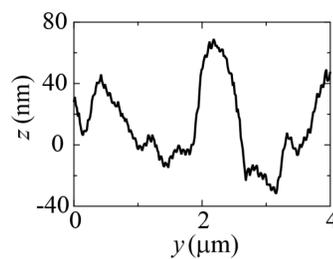
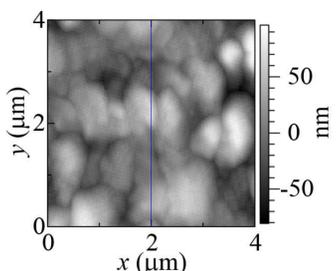
Thin film growing methods



Fabrication of thin films by molecular beam epitaxy (MBE)

- ✓ High vacuum : $2 \times 10^{-6} \text{ Pa}$
- ✓ Stoichiometric atomic deposition rate ratio
 $\text{Yb:Ni:Al} = 1:3:9$
- ✓ Slow deposition rate : $\sim 0.2 \text{ \AA/sec}$
- ✓ c -plane sapphire substrate
- ✓ Substrate temperature : 750°C
- ✓ Film thickness : 200 nm

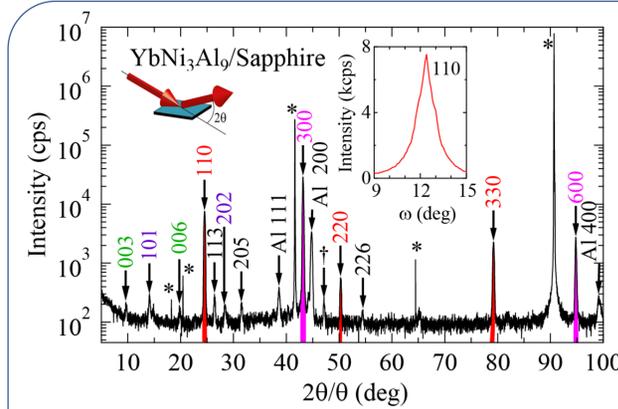
Surface flatness



AFM image showed ...

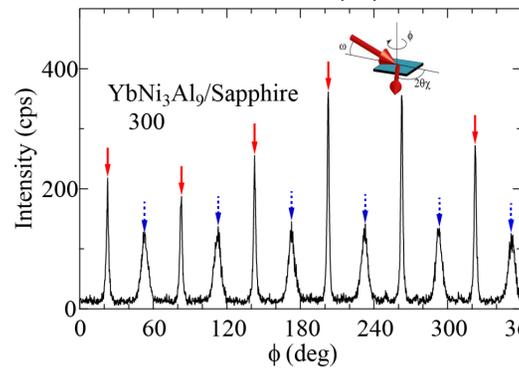
- ✓ An island-like morphology on the surface
 Typical size of $0.5\text{--}1 \text{ mm}$ in diameter
- ✓ The island height : $40 \sim 120 \text{ nm}$

Film orientation



Interplane XRD

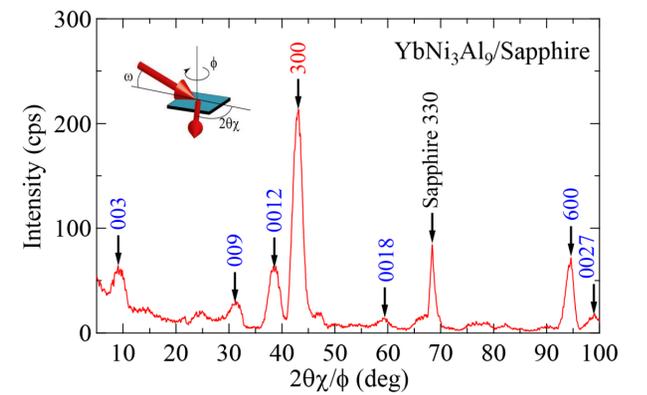
- ✓ $hh0$ and $3h00$ main peaks
- ✓ High orientation : 0.73° FWHM of the rocking curve
 → Uniaxial orientation perpendicular to the surface



Φ scan

- ✓ Two sets of six peaks
 → Reflect six-fold symmetry of the substrate

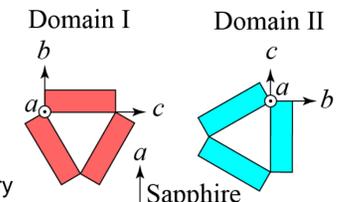
* a [100]



Inplane XRD

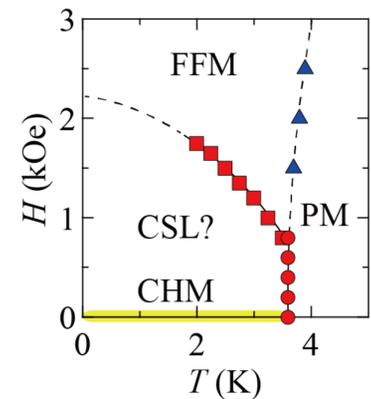
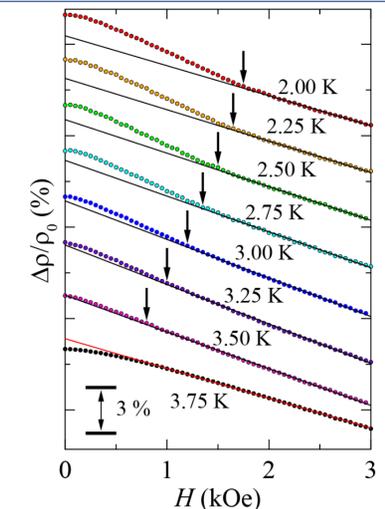
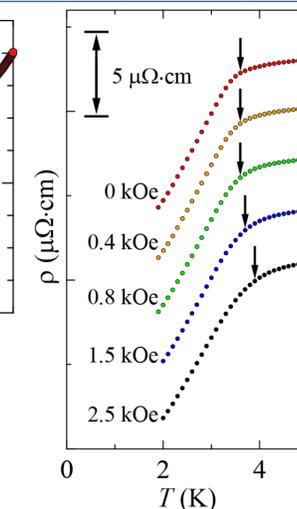
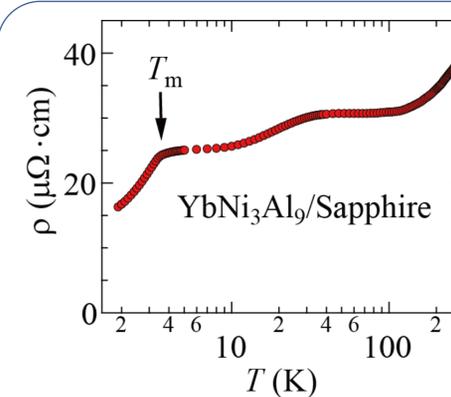
- ✓ $3h00$ and $00l$ main peaks

Epitaxial domains



Domain I	Domain II
$a_{\text{YbNi}_3\text{Al}_9} \parallel c_{\text{sapphire}}$	$a_{\text{YbNi}_3\text{Al}_9} \parallel c_{\text{sapphire}}$
$b_{\text{YbNi}_3\text{Al}_9} \parallel a_{\text{sapphire}}$	$b_{\text{YbNi}_3\text{Al}_9} \parallel b_{\text{sapphire}}$
$c_{\text{YbNi}_3\text{Al}_9} \parallel b_{\text{sapphire}}$	$c_{\text{YbNi}_3\text{Al}_9} \parallel a_{\text{sapphire}}$

Magnetic phase diagram



- ✓ ρ has a maximum at $\sim 40 \text{ K}$.
 → Dense Kondo effect
- ✓ Kink at $T_m = 3.6 \text{ K}$
 → Chiral helimagnetic (CHM) order
- ✓ Negative magnetoresistance (MR)
- ✓ The slope of the MR exhibits a finite change at the critical field H_c
 → Phase transition between an ordered and forced ferromagnetic (FFM) states.
- ✓ The H - T phase diagram qualitatively reproduced that of bulk crystals.
 → Chiral soliton lattice (CSL) state probably arises even in thin films

Summary and future prospects

- ✓ We have achieved in growing thin films of the heavy fermion chiral magnet YbNi_3Al_9 .
- ✓ Chiral soliton lattice (CSL) state probably arises even in thin films.
- ✓ The establishment of a thin film growth method paves way for device applications (e.g. multivalued memory using the topological CSL state)
- ✓ Carrier density control with the use of electric fields may be available in thin films.